



Data-driven measurements of the prompt photon identification efficiency in ATLAS

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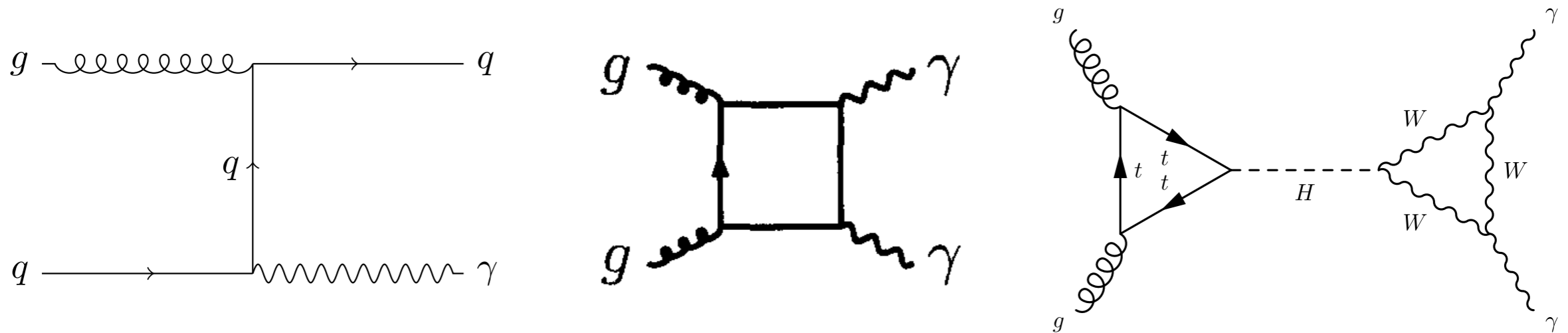


A few words about Kun

- Master at USTC
- Came to LPNHE May-June 2011 with Yanwen for a pre-thesis stage
- Stayed at LPNHE till mid Feb. 2012 - now at USTC for a few months
- Started his co-tutorship Ph.D. at UPMC (Paris-6) in September 2011
- Worked hard on
 - photon efficiency
 - photon trigger optimization for 2012 running
 - ATLAS authorship qualification work (trigger software development/debugging)
 - unfolding of SM diphoton cross section with ATLAS 2011 data

Motivation

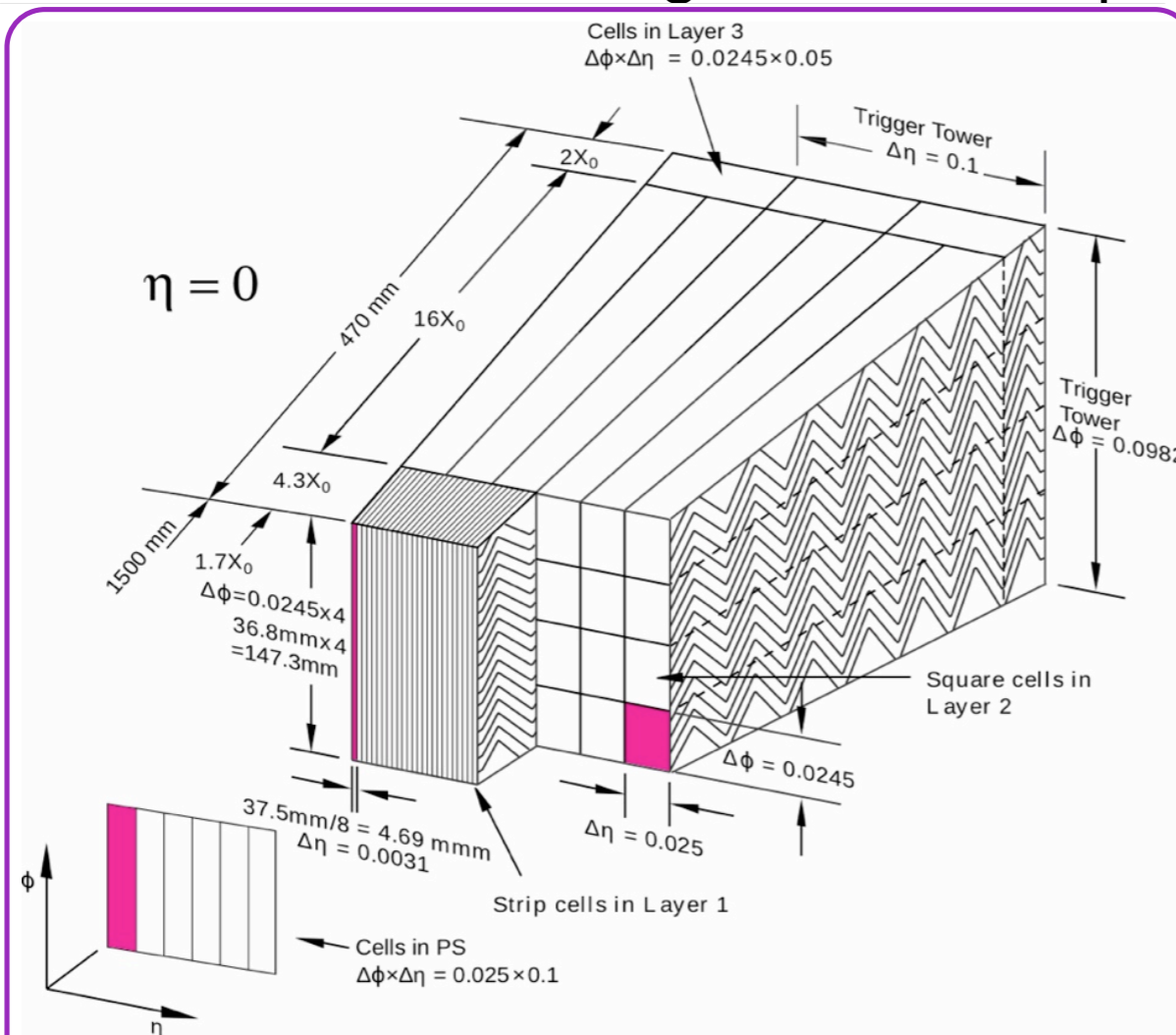
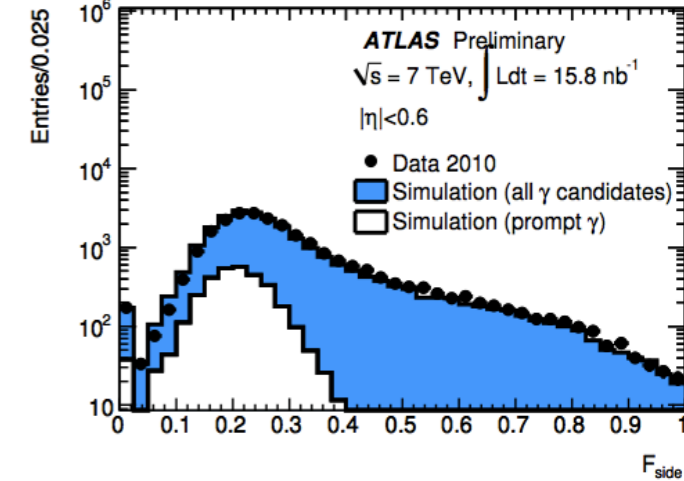
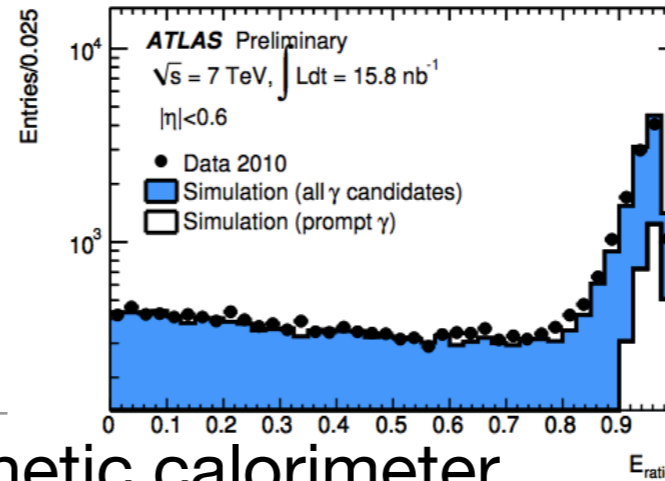
- Prompt photons = photons not originated from hadron decays
- Measurements with prompt photons (examples):
 - inclusive $\gamma/\gamma\gamma$ and γ +jet xsections: tests of pQCD, extract gluon PDF
 - diphoton resonances: search for Higgs, Graviton, ...



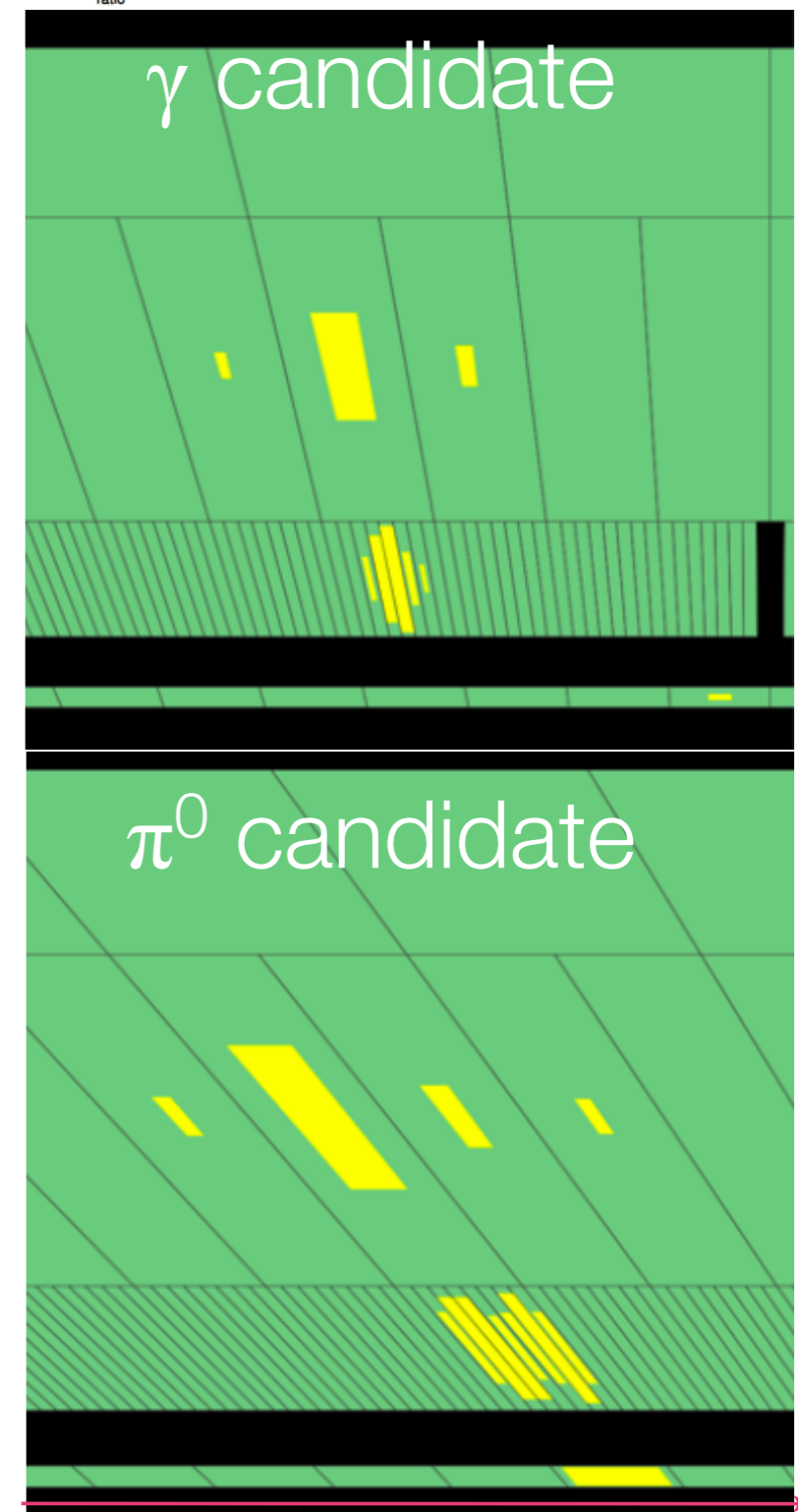
- Photon identification (ID): discriminate against large bkg from jets ($\pi^0 \rightarrow \gamma\gamma$)
- Photon (identification) efficiency needed to compute xsections and compare them to predictions (pQCD; SM vs fermiophobic Higgs; ...)

Photon ID in ATLAS

- Exploit segmentation of electromagnetic calorimeter
- Based on 9 discriminating “shower shape” variables

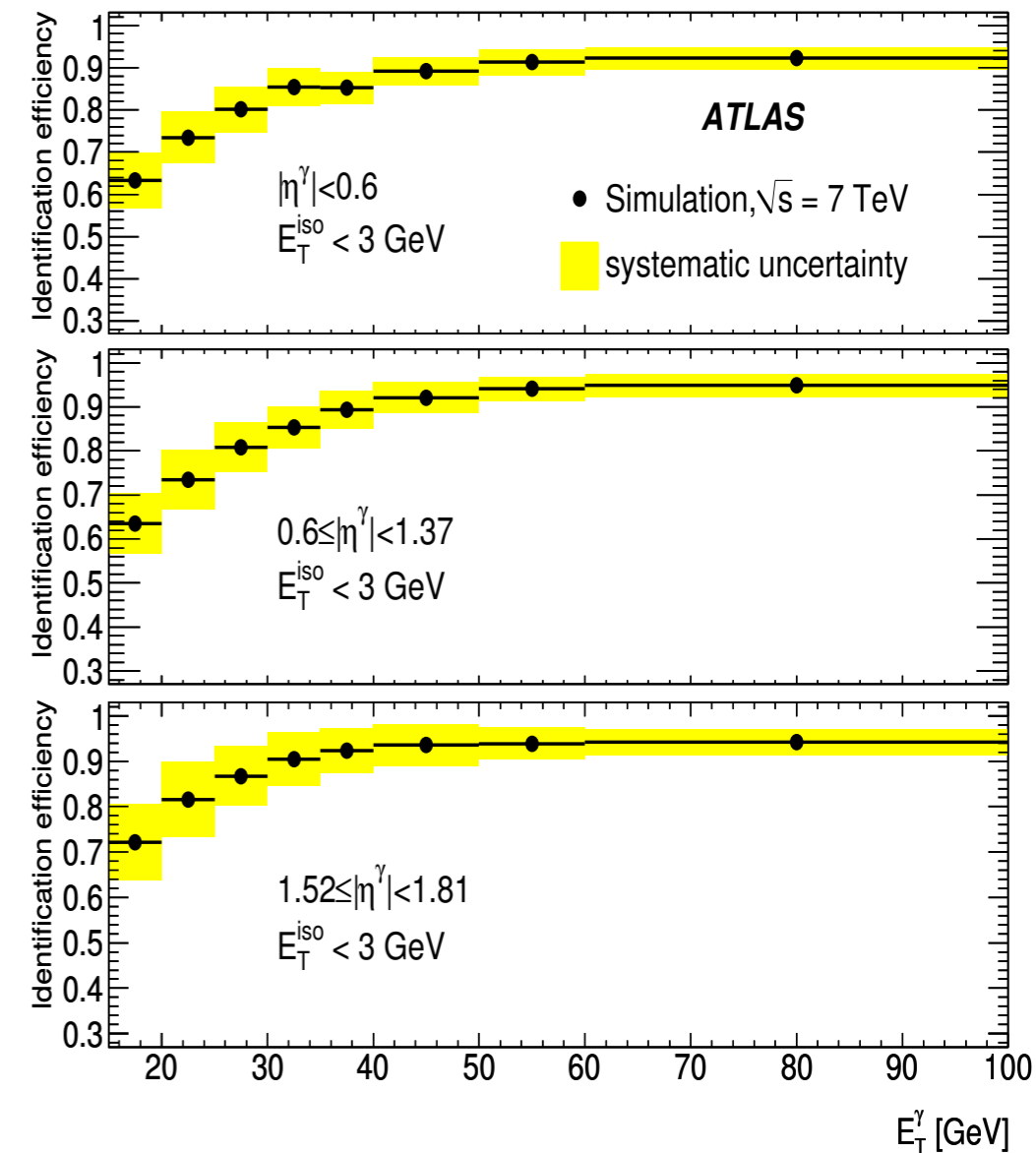


- **Pb-LAr EM calorimeter**
 - very fine layer 1 segmentation up to $|\eta| = 2.37$
 - ✓ γ energy/direction measurement
 - ✓ π^0/γ discrimination (shower shape)



Measuring the photon identification efficiency

- No abundant, clean source of photons to measure efficiencies with tag&probe technique (unlike e, μ leptons: $Z \rightarrow ll$)
 - cleanest source: radiative Z decays ($Z \rightarrow ll\gamma$)
But: low stat (requires $> \text{fb}^{-1}$), limited $p_{T\gamma}$
 - analysis of 2010 data (37 pb^{-1}): efficiency from simulation
 - correct (“fudge”) shower shape distributions by average data-MC difference observed in photon-enriched samples
 - large systematic uncertainties (up to $\sim 15\%$)
- 2011 dataset: $\sim 5 \text{ fb}^{-1}$
 - start to have enough radiative Z decays (for $E_{T\gamma} < 50 \text{ GeV}$)
 - analyses not statistically limited \Rightarrow need to reduce systematic uncertainties to few % level

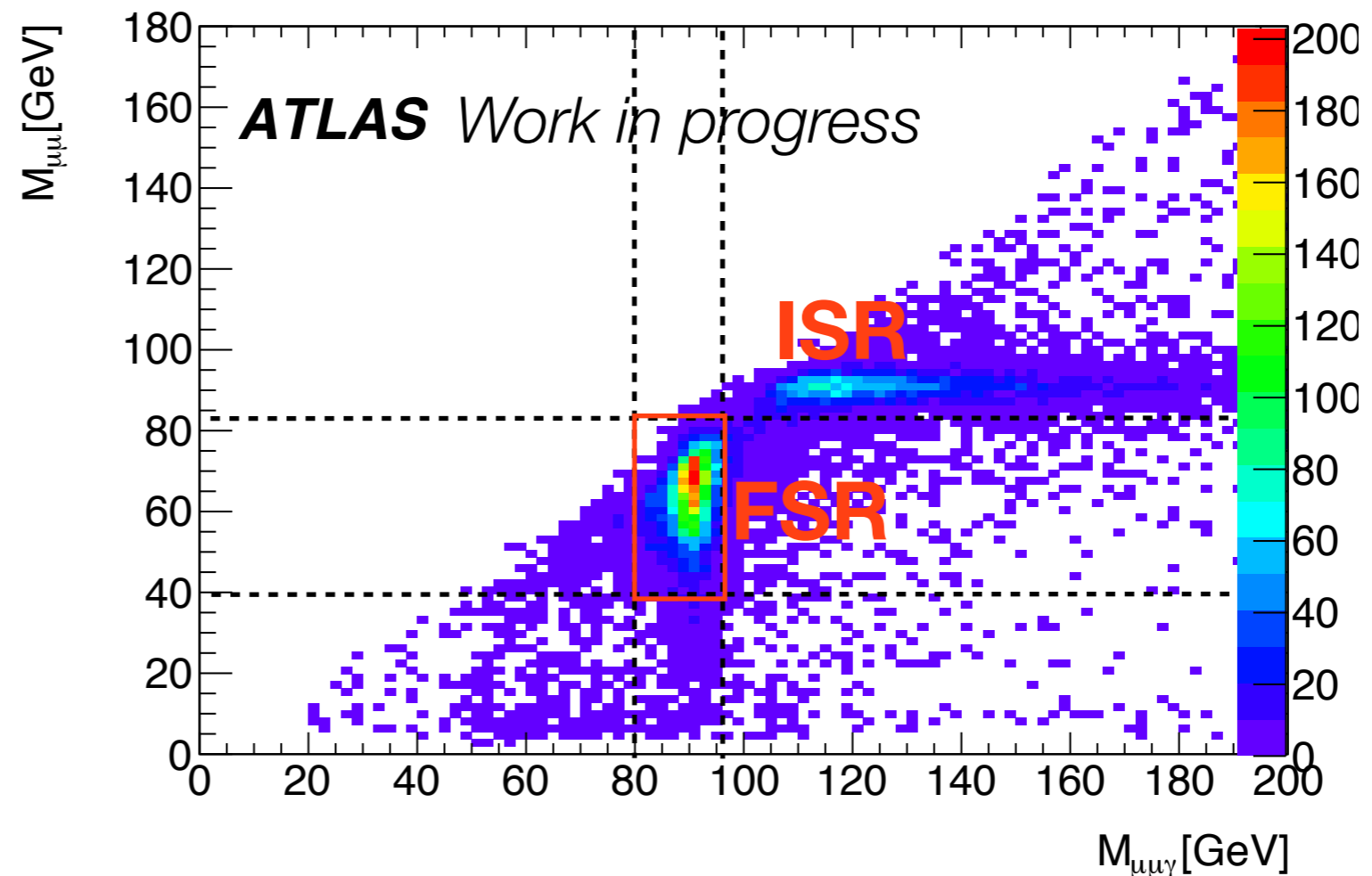


Data-driven measurements of the photon ID efficiency in ATLAS

- Radiative Z decays
 - select $Z \rightarrow l\bar{l}\gamma$ sample using requirements on leptons and kinematics of $l\bar{l}$
 - gamma candidate = clean probe to measure efficiency
- Matrix method
 - select a photon-enriched sample with events passing photon triggers (very loose selection)
 - estimate residual bkg contamination in selected sample, both before and after application of ID criteria, using a discriminant variable for which the different signal and background efficiencies are known
- Electron extrapolation
 - select pure sample of electrons from $Z \rightarrow ee$ (with T&P)
 - “transform” electron shower shapes into photon shower shapes

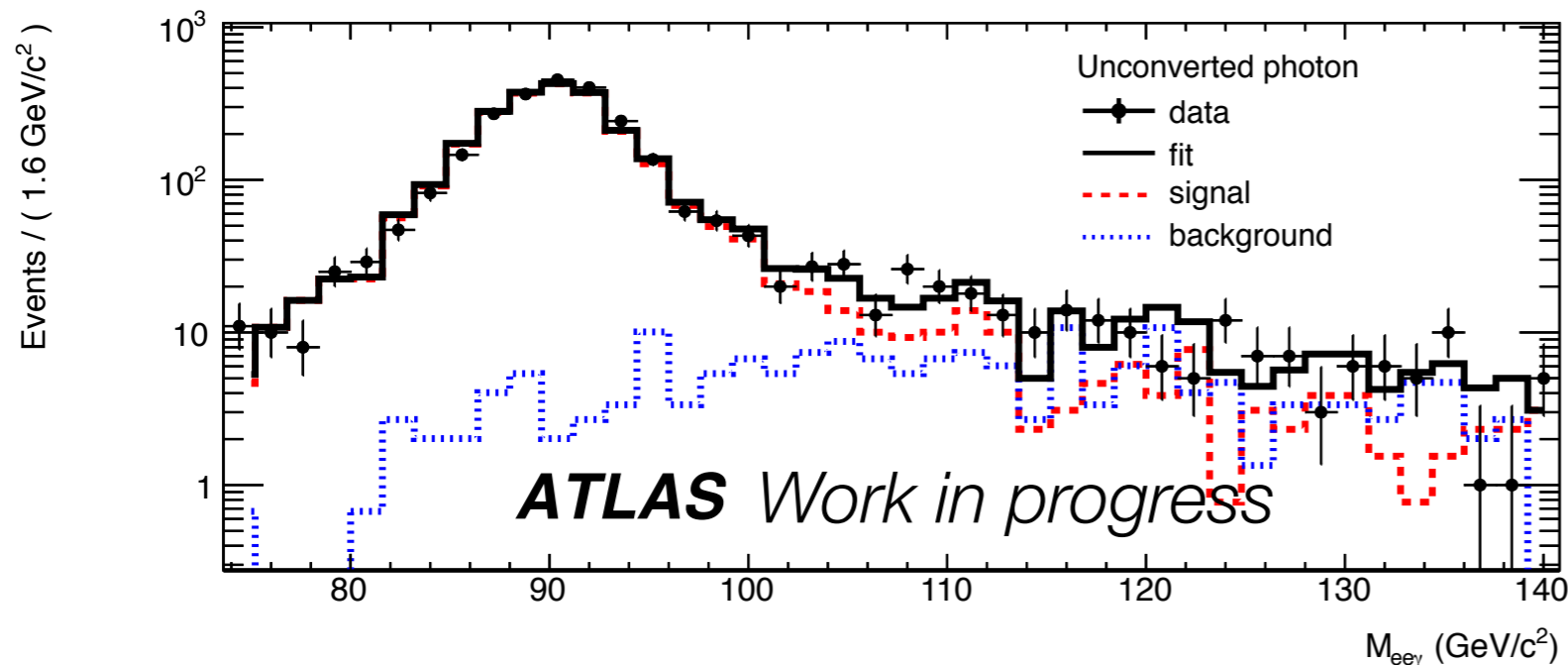
Photon efficiency from radiative Z decays

- single electron or muon triggers
- good electron or muon (in tracker, EM calorimeter/muon spectrometer)
 - originating from primary vertex
 - isolated (reject leptons from heavy flavor decays)
 - not too close to the photon (avoid bias on photon shower shapes)
- $E_{T}^{\gamma,l} > 15$ GeV
- $80 < M_{ll\gamma} < 96$ GeV
- $40 < M_{ll} < 83$ GeV
- ~11k probes in total

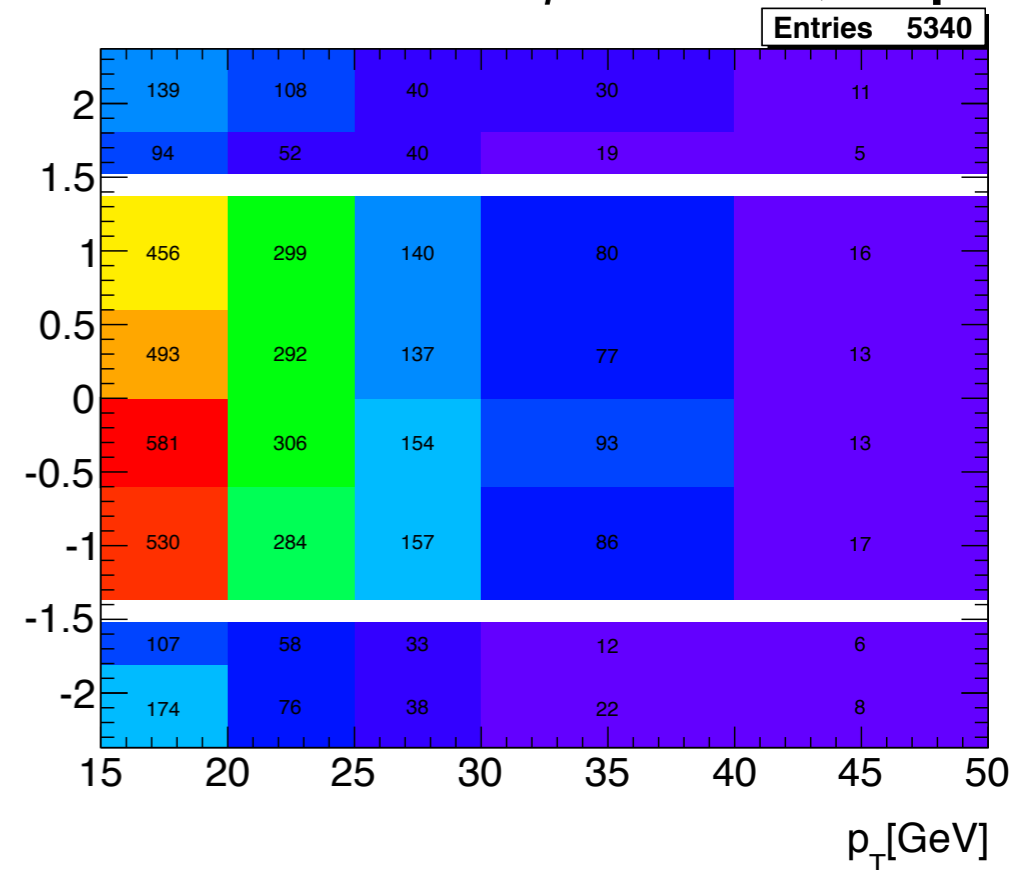


Photon efficiency from radiative Z decays

- Typical probe E_T/η distribution peaks at low E_T :
- Residual bkg from Z+jets; estimated from template fit to $M_{ll\gamma}$ using MC templates



unconverted photons, $l=\mu$



- purity typically $> 98\%$; error on efficiency when assuming $P=1$: 1-1.5%
- Results consistent for $l=e,\mu \Rightarrow$ combined. Statistically limited (plots later)

Photon efficiency from matrix method

- After selecting photon-enriched sample (photon triggers: very loose cuts on few shower shapes), use track isolation as discriminating variable to count signal (S) and background (B) that pass/fail the identification (T) criteria
- System of 4 equations in 4 unknowns (if track iso efficiencies are known)

$$\begin{array}{l}
 N_{pass}^T = N_{pass}^S + N_{pass}^B \\
 N_{fail}^T = N_{fail}^S + N_{fail}^B
 \end{array}
 \xrightarrow[\text{isolation cut}]{\text{pass track}}
 \begin{array}{l}
 N_{pass}^{Iso} = \epsilon_p^s * N_{pass}^S + \epsilon_p^b * N_{pass}^B \\
 N_{fail}^{Iso} = \epsilon_f^s * N_{fail}^S + \epsilon_f^b * N_{fail}^B
 \end{array}$$

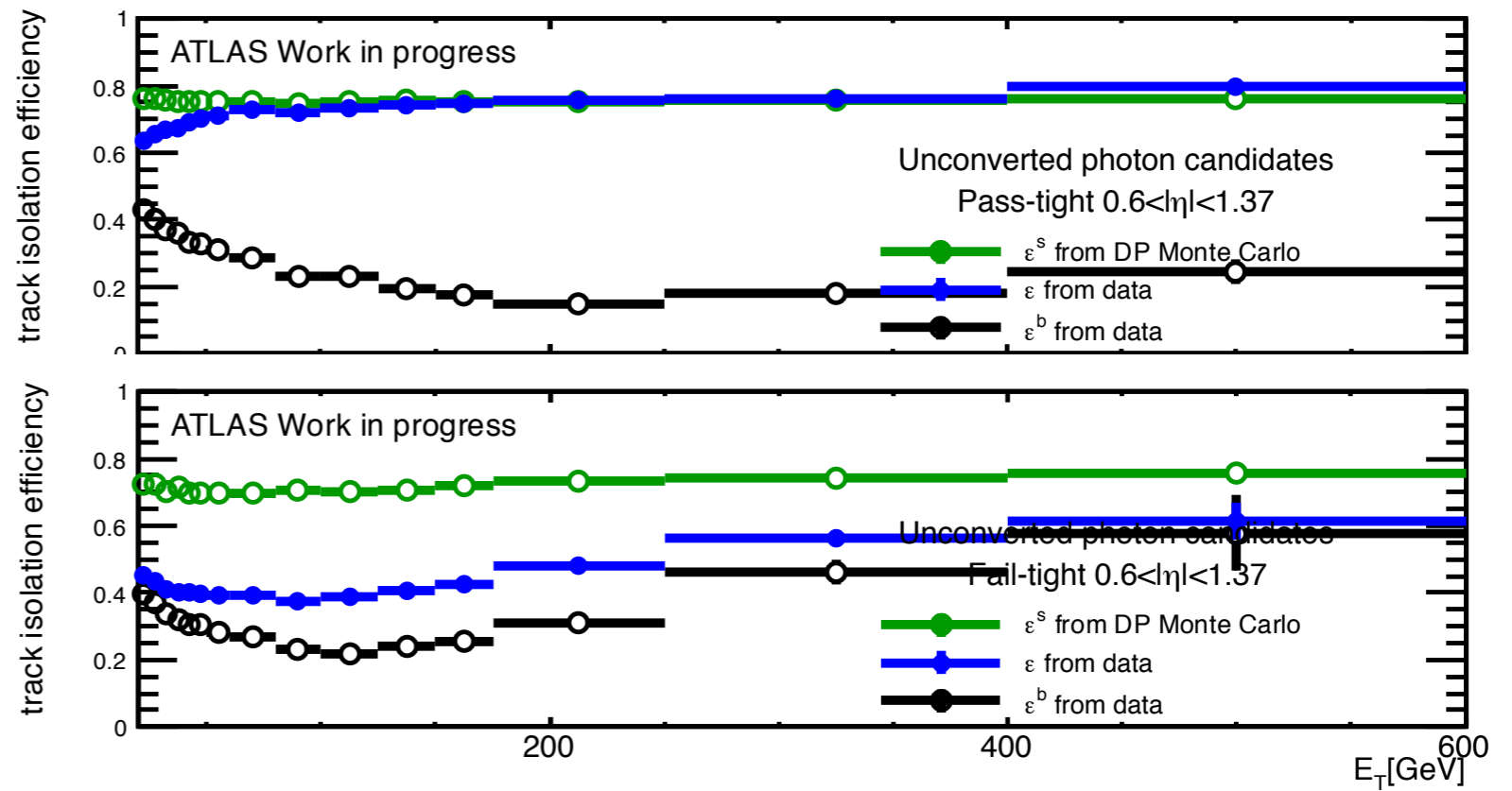
$$\begin{array}{l}
 N_{pass}^S = \frac{N_{pass}^{Iso} - \epsilon_p^b * N_{pass}^T}{\epsilon_p^s - \epsilon_p^b} \\
 N_{fail}^S = \frac{N_{fail}^{Iso} - \epsilon_f^b * N_{fail}^T}{\epsilon_f^s - \epsilon_f^b}
 \end{array}
 \xrightarrow{\quad}
 \epsilon^{tight-ID} = \frac{N_{pass}^S}{N_{pass}^S + N_{fail}^S}$$

$$\begin{array}{l}
 P = \frac{N_{pass}^S}{N_{pass}^T} = \frac{\epsilon_p^s - \epsilon_p^b}{\epsilon_p^s - \epsilon_p^b} \\
 F = \frac{N_{fail}^S}{N_{fail}^T} = \frac{\epsilon_f^s - \epsilon_f^b}{\epsilon_f^s - \epsilon_f^b}
 \end{array}$$

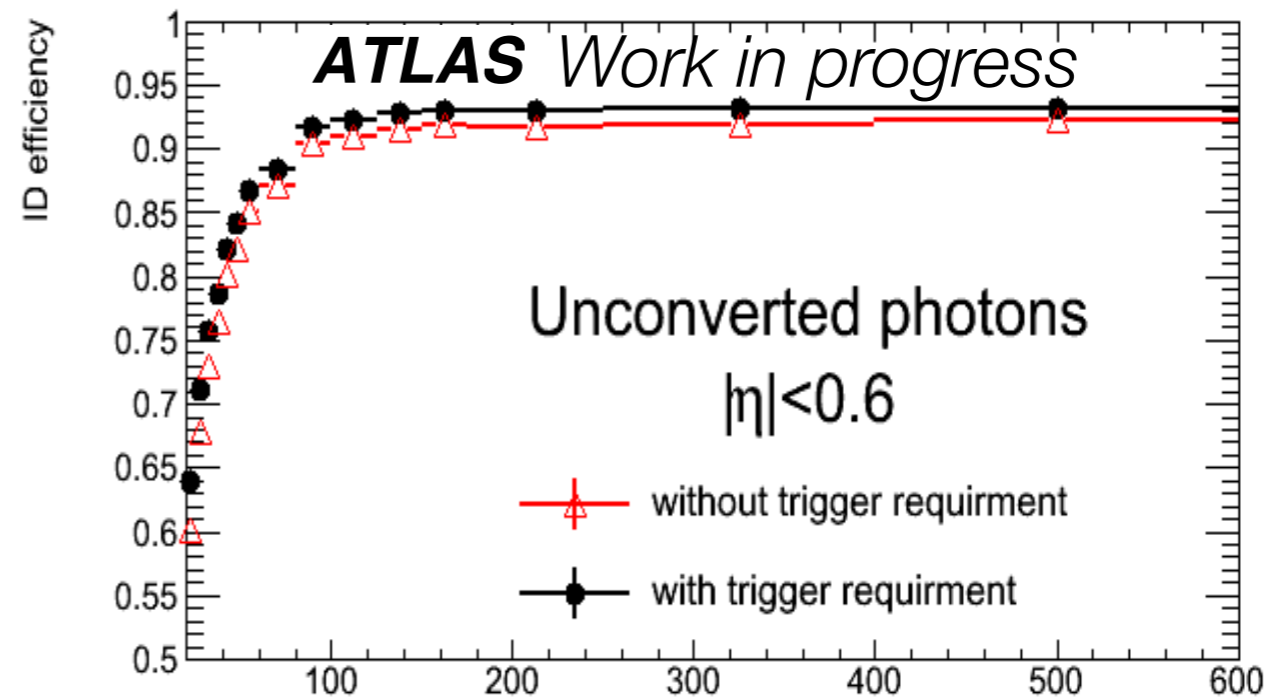
- Prompt photon track iso efficiencies from signal MC (systematic uncertainty from data/MC efficiency difference for electrons from $Z \rightarrow ee$)
- Background track iso efficiencies from data control sample enriched with jets (systematic uncertainty from closure tests on MC)

Ingredients for efficiency measurement with matrix method

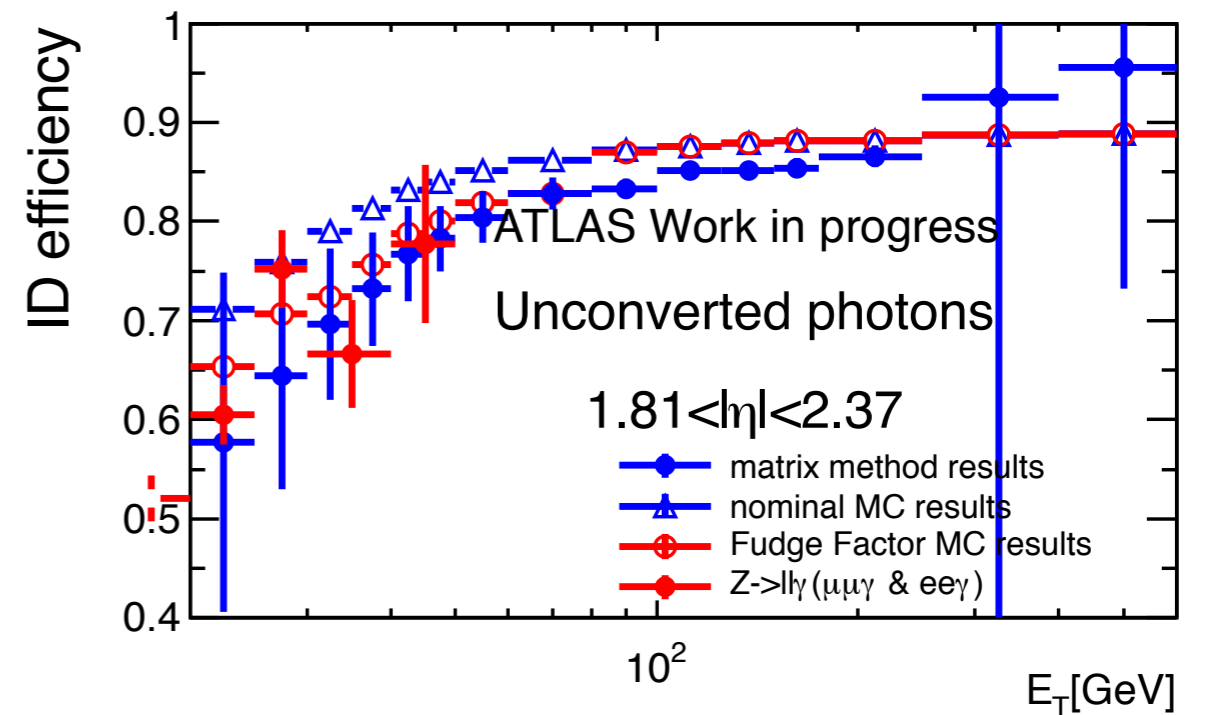
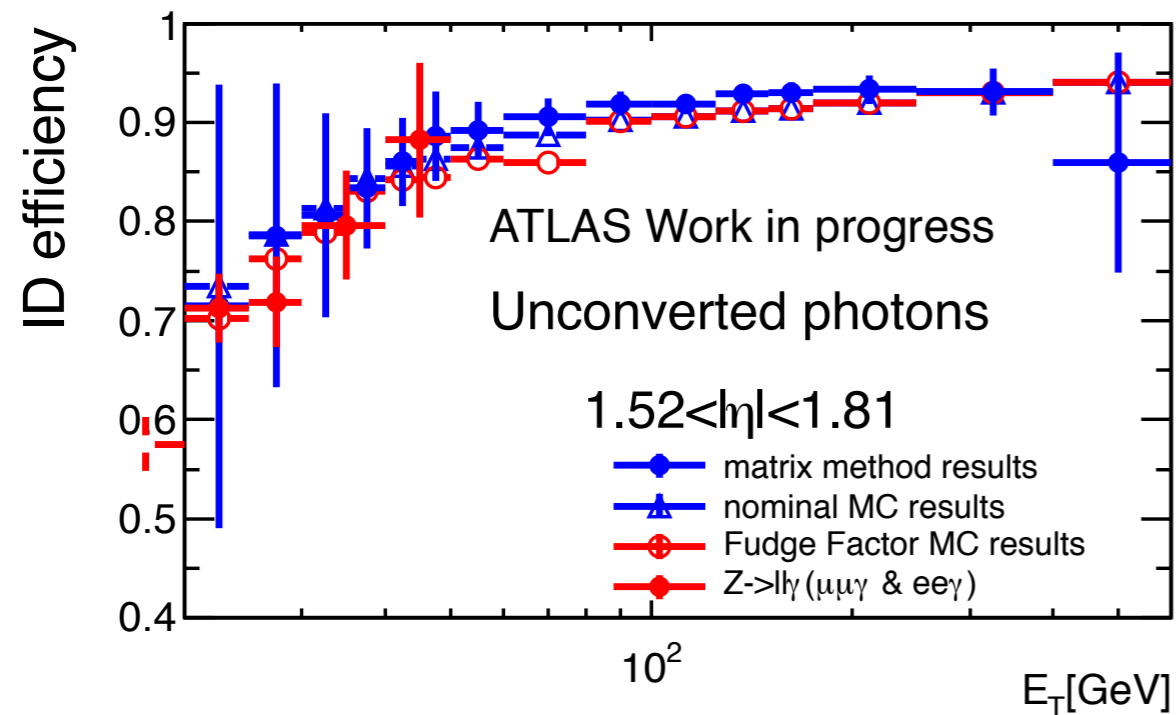
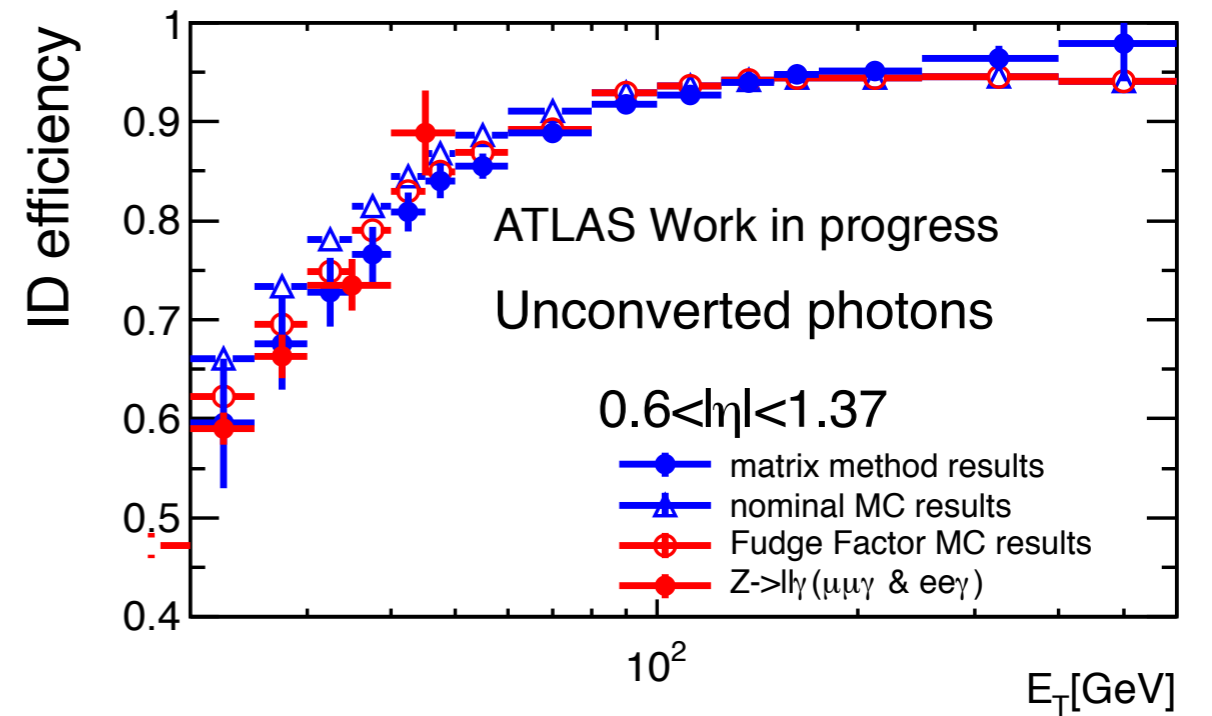
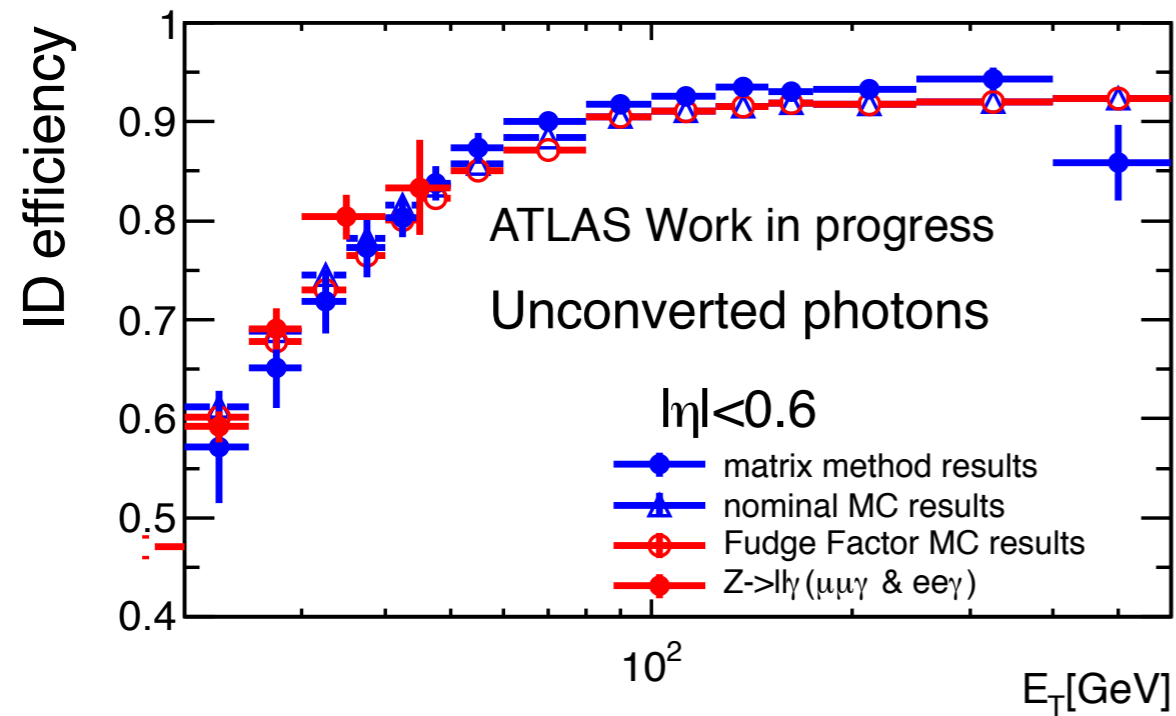
- Track isolation efficiencies



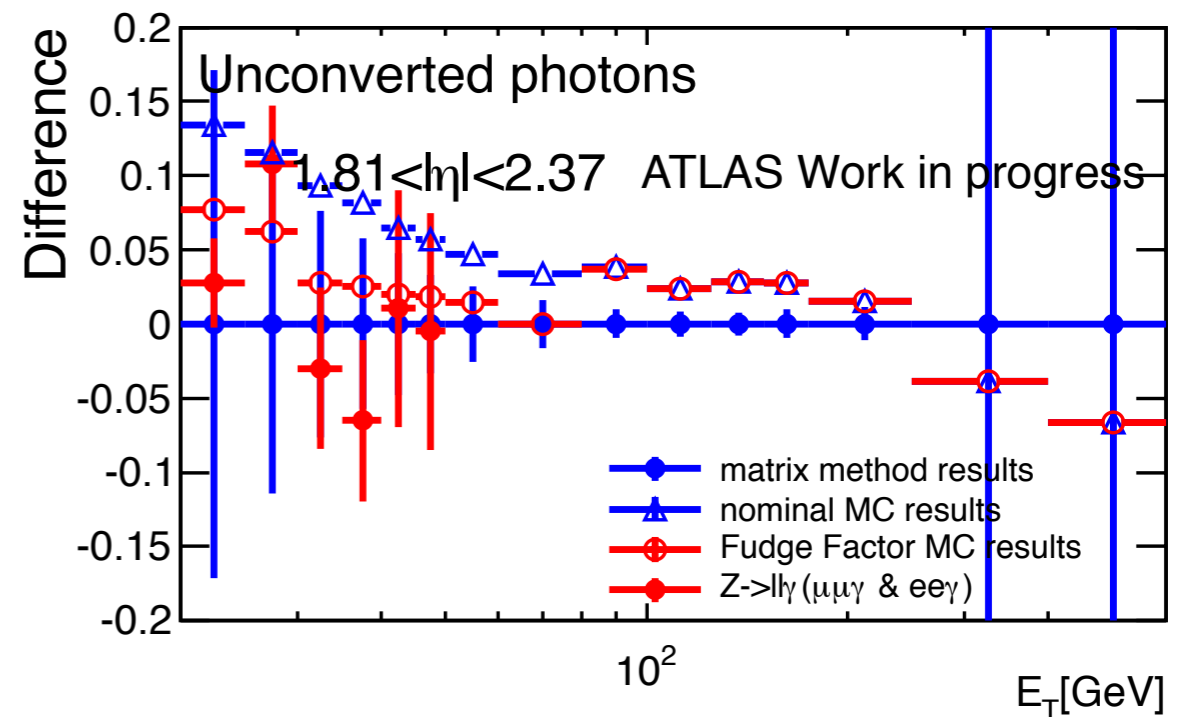
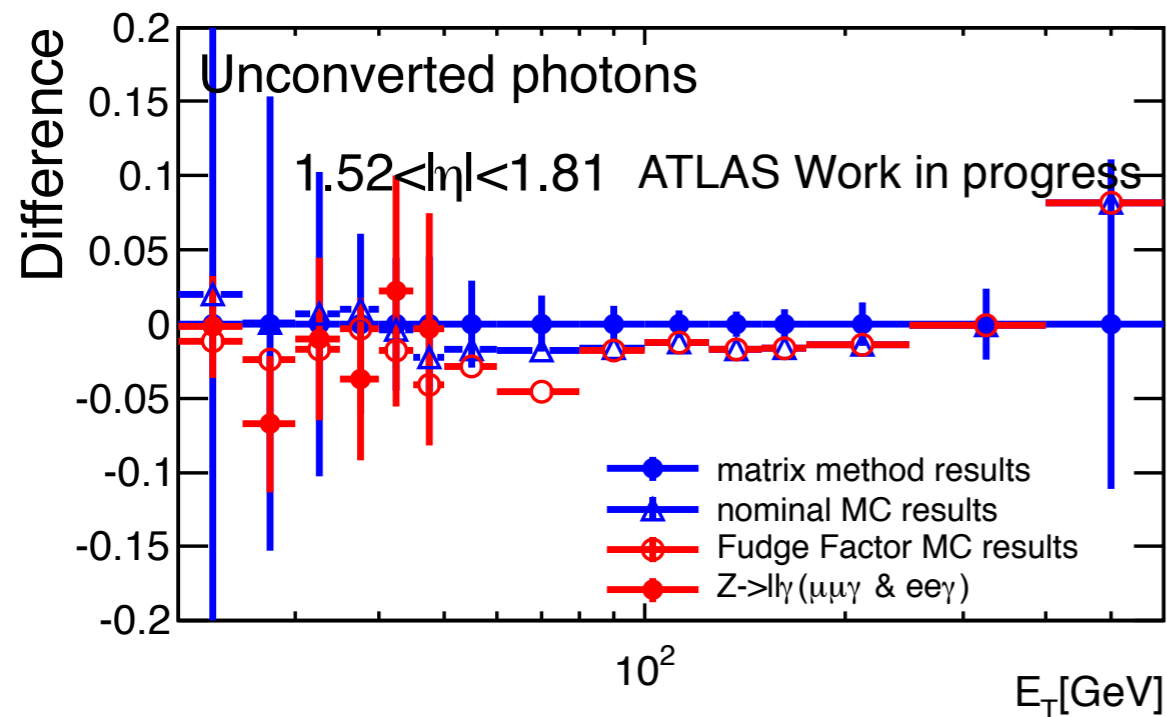
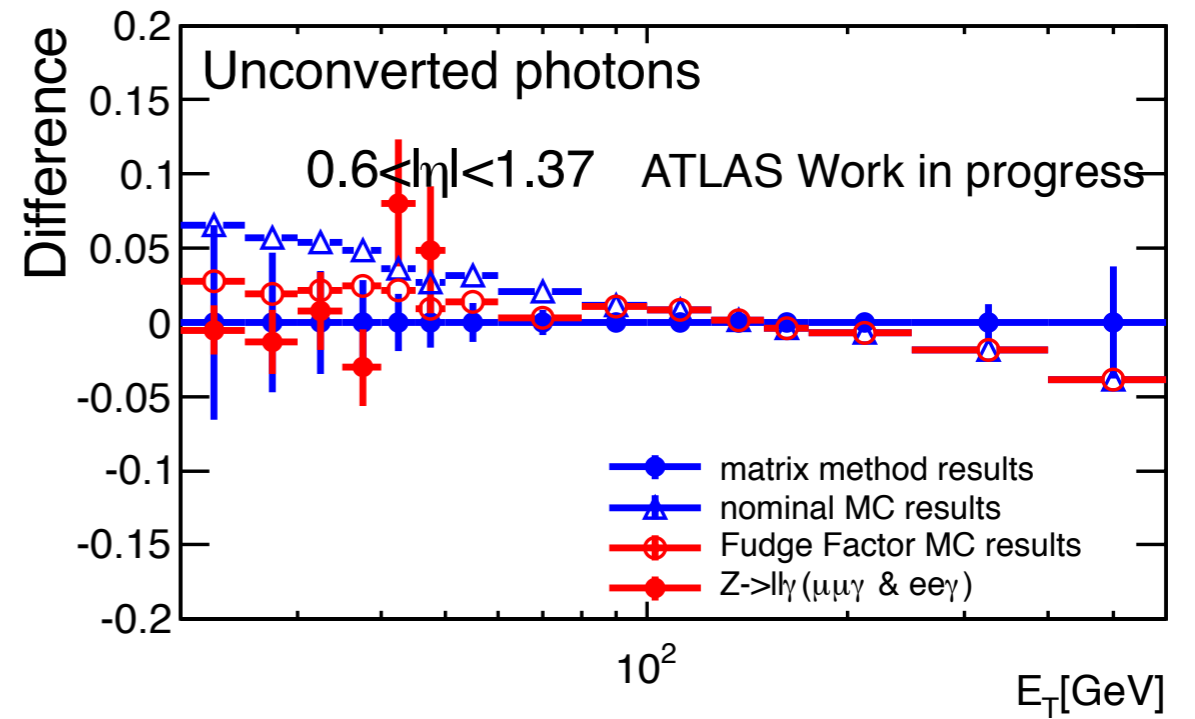
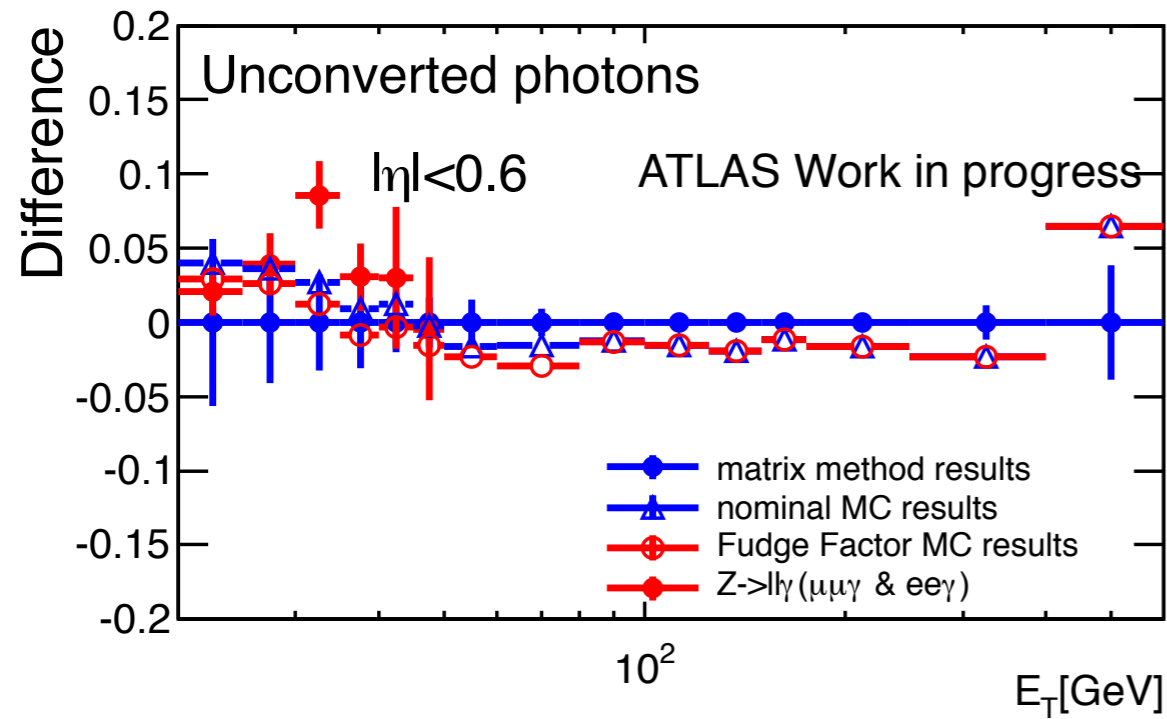
- Efficiency of trigger preselection (from MC; to be checked with radiative Z decays at low E_T)



Results



Results



Conclusion

- Prompt photon identification efficiency measured with 2 data-driven methods
 - radiative Z decays \Rightarrow precise at low E_T (limited at high E_T by statistics)
 - matrix method \Rightarrow precise at high E_T (limited at low E_T by purity uncertainty)
- Results from 2 methods consistent within few %
 - can reduce systematic uncertainties significantly wrt 2010 analyses
- MC estimates typically within 5% from data results
 - confirms validity of 2010 results based on MC efficiencies (with conservatively large systematic uncertainties)

Backup

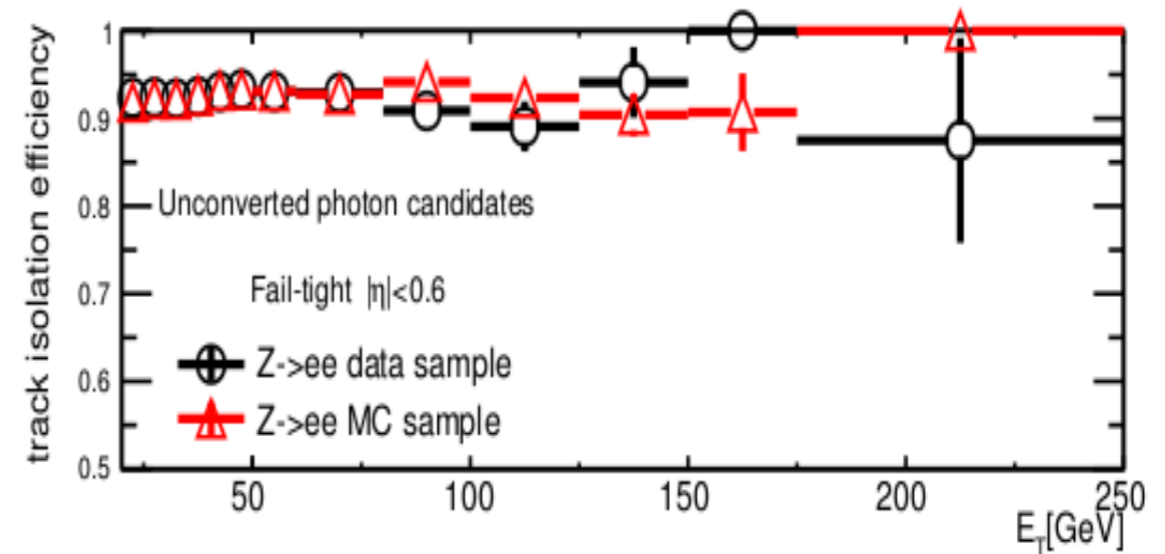
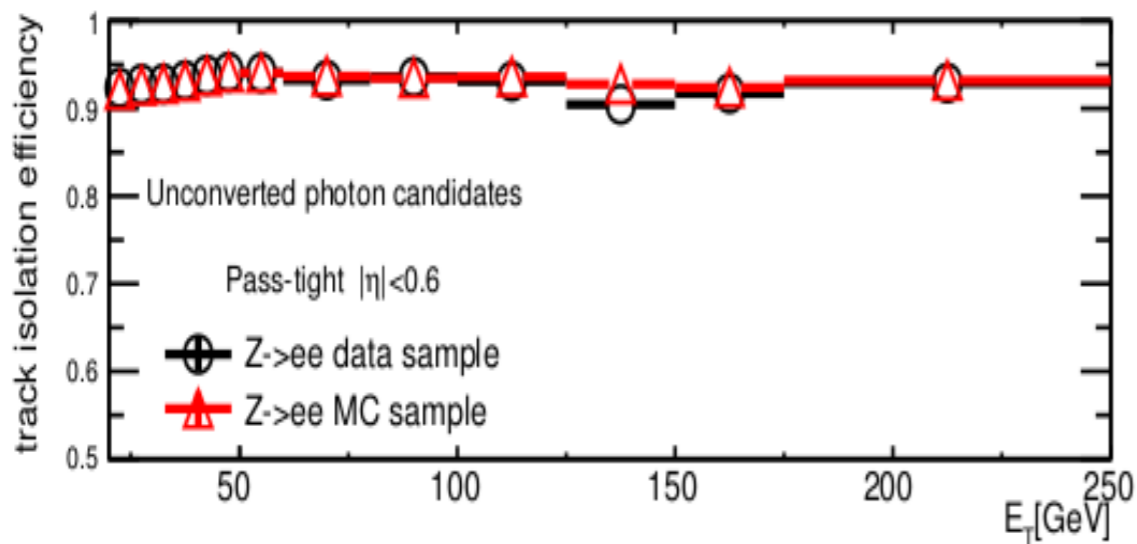
ε_p^s and ε_f^s from DP simulated sample

- Central values from truth reconstructed isolated photons
 - * DP 17 ($E_t > 20$ GeV)
 - * DP 35 ($E_t > 45$ GeV)
 - * DP 70 ($E_t > 90$ GeV)
 - * DP 140 ($E_t > 150$ GeV)
 - * DP 280 ($E_t > 290$ GeV)
 - * DP 500 ($E_t > 510$ GeV)
- Systematic uncertainties:
 - * Possible data/MC discrepancies:
 - * from the difference between ε^s in Z->ee data and MC
 - * plots are shown in next slide
 - * difference between ε^s for 1 / 2 track conversion
 - * only for converted photons
 - * from difference between ε^s for unconverted and converted photons

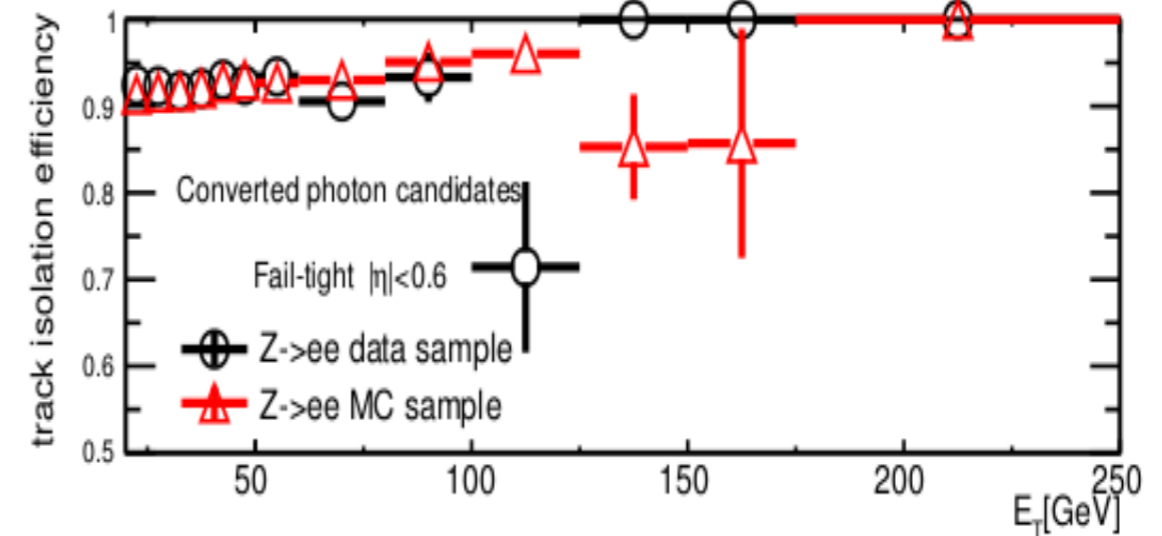
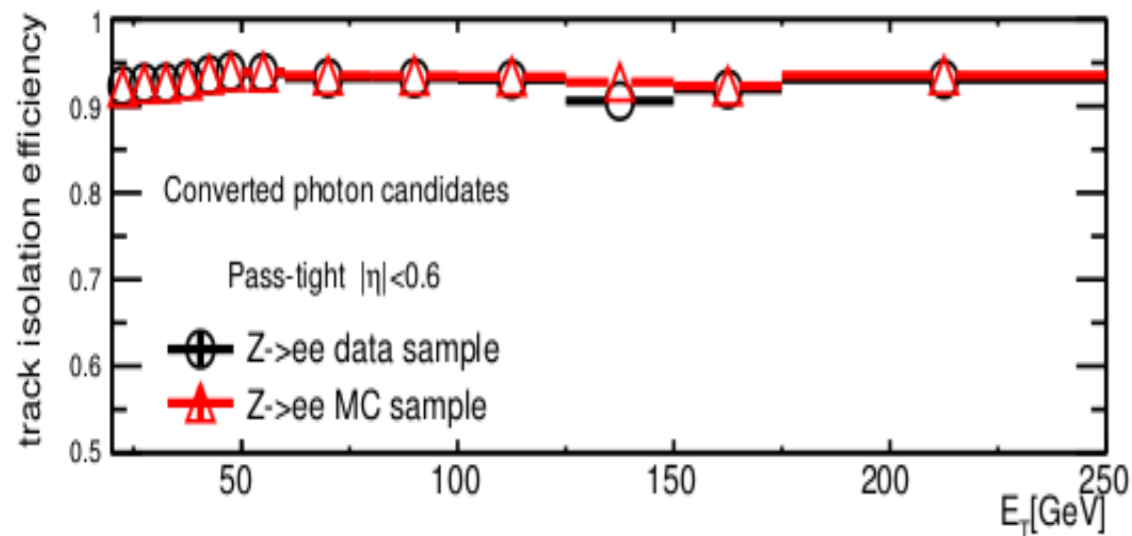
ε_p^S and ε_f^S from DP simulated sample

- Track isolation efficiency from probe electrons in Z->ee data and MC passing or not the unconverted/converted photon identification

unconverted photon

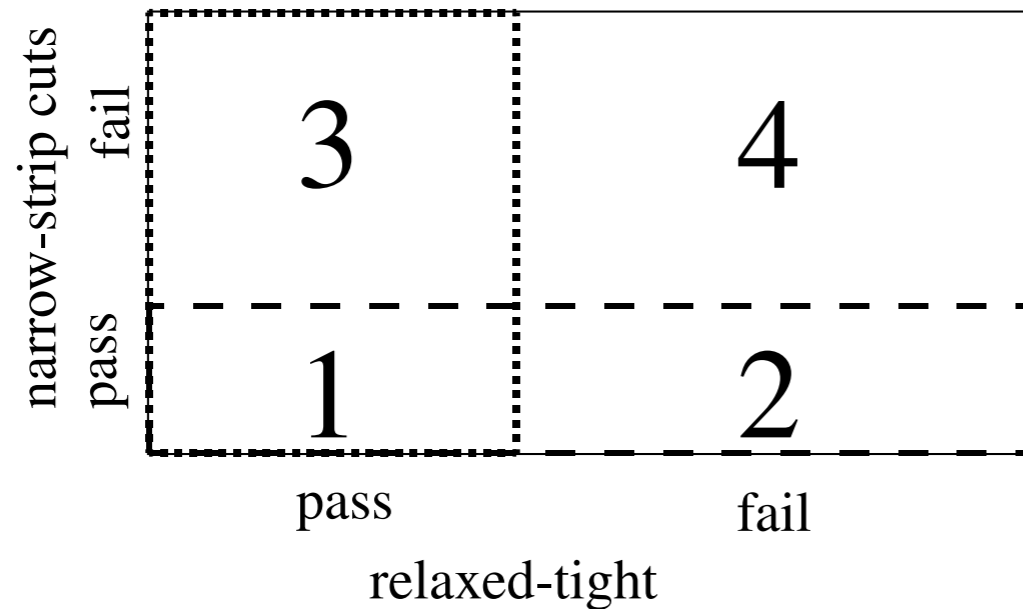


converted photon



ε_p^b and ε_f^b from bkg-enriched data sample

- Select photon candidates in data by reversing narrow strips variables cuts
 - * four variables: ΔE , f_{side} , W_{s3} and E_{ratio}
 - * relaxed-tight cut: ID tight cuts except above narrow-strips variables cuts



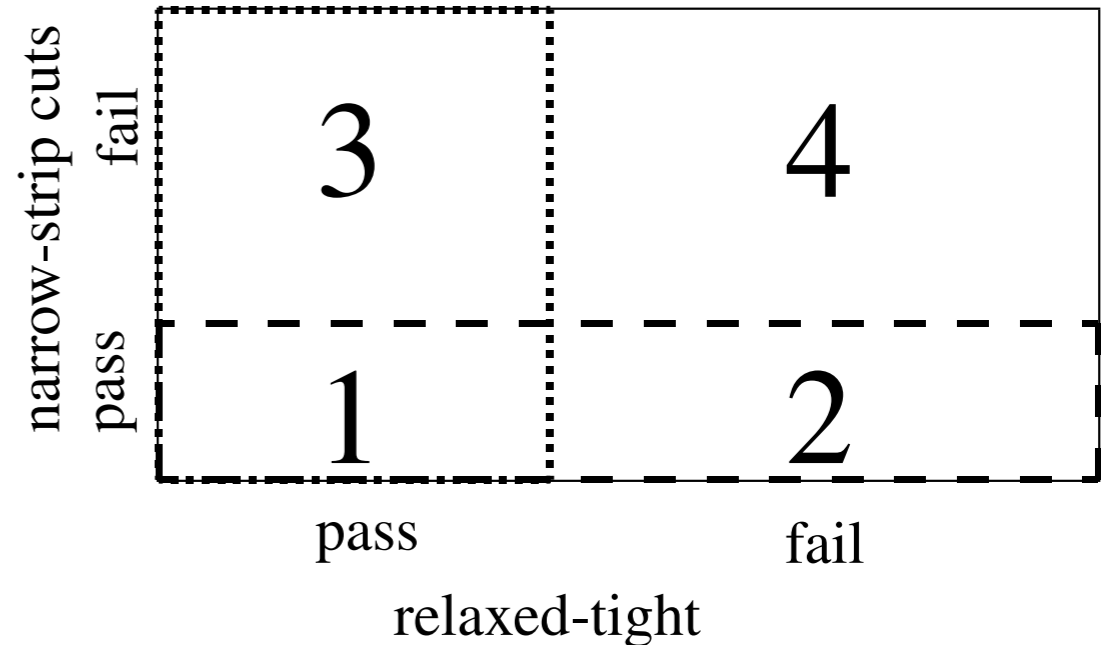
- pass relaxed-tight cuts
- ▤ pass all cuts on narrow-strip variables
- 1: pass tight cuts
- 2: pass narrow-strip variable cuts but fail relaxed-tight cuts
- 3: pass relaxed-tight but fail narrow-strip cuts
- 4: fail relaxed-tight and fail narrow-strip cutsvariables

* signal leakage correction (see next slide)

- Systematic uncertainty:

* bias on ε^b checked with simulated JF MC samples: comparing the difference of ε^b obtained with truth match and with the same procedure used in data

$$\begin{aligned} & \text{JF17}(E_t > 20\text{GeV}) + \text{JF35}(E_t > 45\text{GeV}) + \text{JF70}(E_t > 90\text{GeV}) + \text{JF140}(E_t > 150\text{GeV}) \\ & + \text{JF240}(E_t > 250\text{GeV}) + \text{JF500}(E_t > 510\text{GeV}) \end{aligned}$$



We introduce a few definitions according to Fig. 3:

- N_A : total number of photon candidates in region 3.
- N_B : total number of photon candidates in region 4.
- ε_p : fraction of photon candidates that are isolated in the tracker after passing tight criteria (region 1).
- ε_f : fraction of photon candidates that are isolated in the tracker after failing tight criteria (region 2+3+4).
- $\varepsilon_p^{b^+}$: fraction of photon candidates in region 3 that are isolated in the tracker.
- $\varepsilon_f^{b^+}$: fraction of photon candidates in region 4 that are isolated in the tracker.

We also remind the previous definitions of:

- N_{pass}^T : total number of photon candidates that pass tight criteria (region 1).
- N_{fail}^T : total number of photon candidates that fail tight criteria (region 2+3+4).

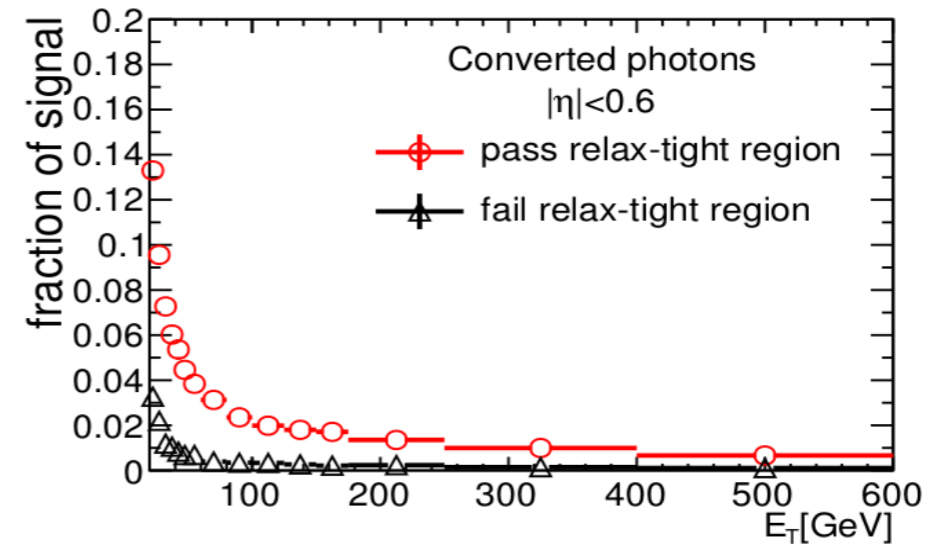
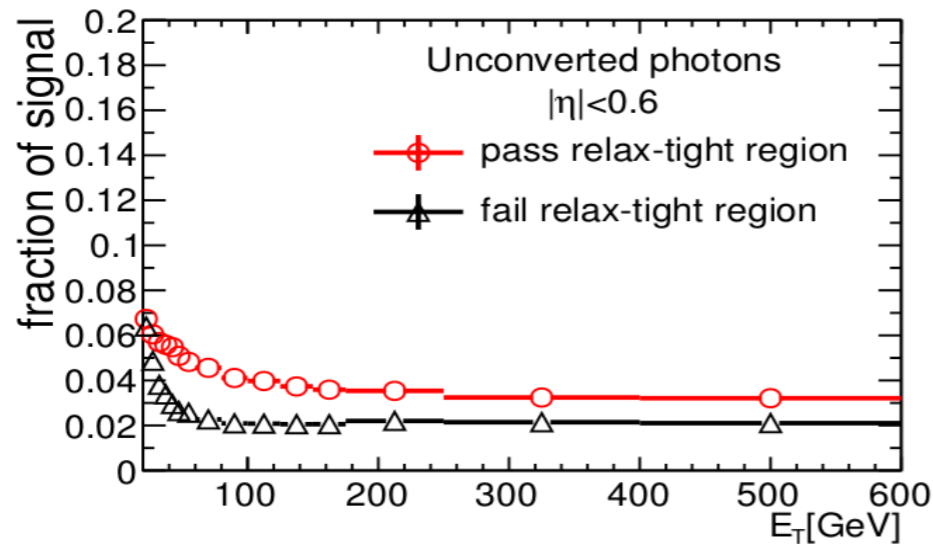
The previous quantities are determined on data.

From the prompt photon MC sample we extract the following quantities for true prompt photons:

- f_p : fraction of prompt photons that leak into region 3.
- f_f : fraction of prompt photons that leak into region 4.
- ε_p^s : track isolation efficiency for prompt photons in region 1.
- ε_f^s : track isolation efficiency for prompt photons in region 2+3+4.
- $\varepsilon_p^{s^+}$: track isolation efficiency for prompt photons in region 3.
- $\varepsilon_f^{s^+}$: track isolation efficiency for prompt photons in region 4.

Signal leakage correction

- Fraction of true photons in bkg control sample passing or failing relaxed-tight criteria



- Signal leakage correction procedure: solve three equations to obtain **3 unknowns** total real photons in passing and failing tight criteria

$$N_s^{total} = \frac{\epsilon_p - \epsilon_p^b}{\epsilon_p^s - \epsilon_p^b} * N_P + \frac{\epsilon_f - \epsilon_f^b}{\epsilon_f^s - \epsilon_f^b} * N_F \quad \dots\dots(1)$$

subtract signal leakage from numerator and denominator

$$\epsilon_p^b = \frac{N_A * \epsilon_p^{b+} - N_s^{total} * f_p * \epsilon_p^{s+}}{N_A - N_s^{total} * f_p} \quad \dots\dots(2)$$

$$\epsilon_f^b = \frac{N_B * \epsilon_f^{b+} - N_s^{total} * f_f * \epsilon_f^{s+}}{N_B - N_s^{total} * f_f} \quad \dots\dots(3)$$

equations are nonlinear, iterative procedure is used with inputs:

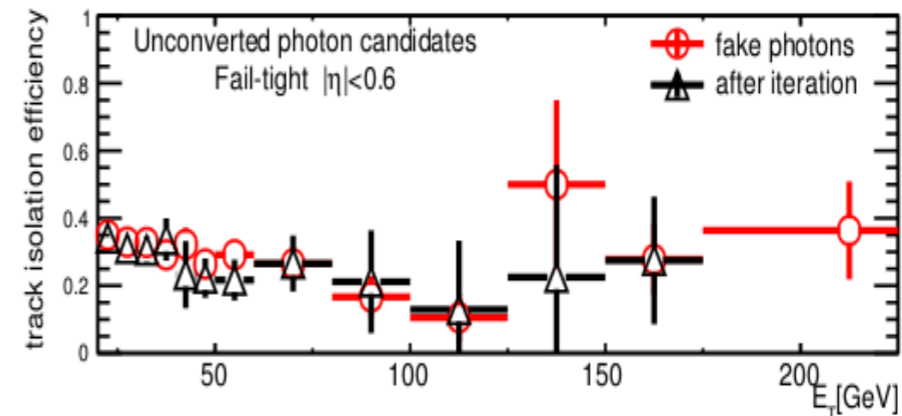
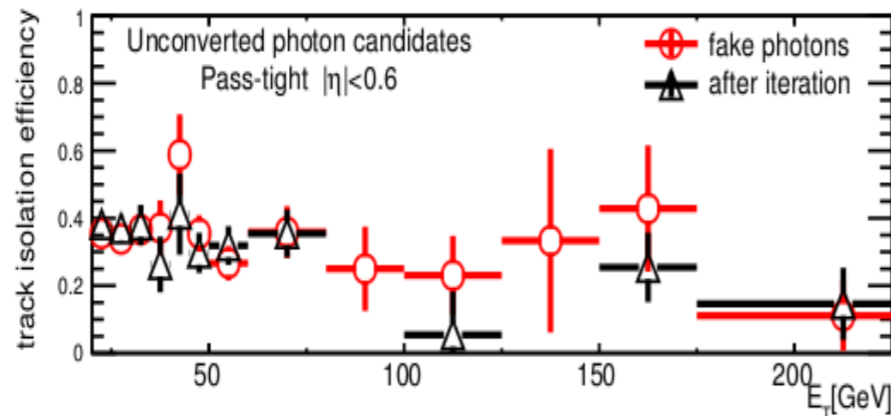
* from DP MC: ϵ_p^{s+} ϵ_f^{s+} f_p f_f

* from JF MC at the beginning: ϵ_p^{b+} ϵ_f^{b+} more and more precise values are solved during iteration (3~5 steps)

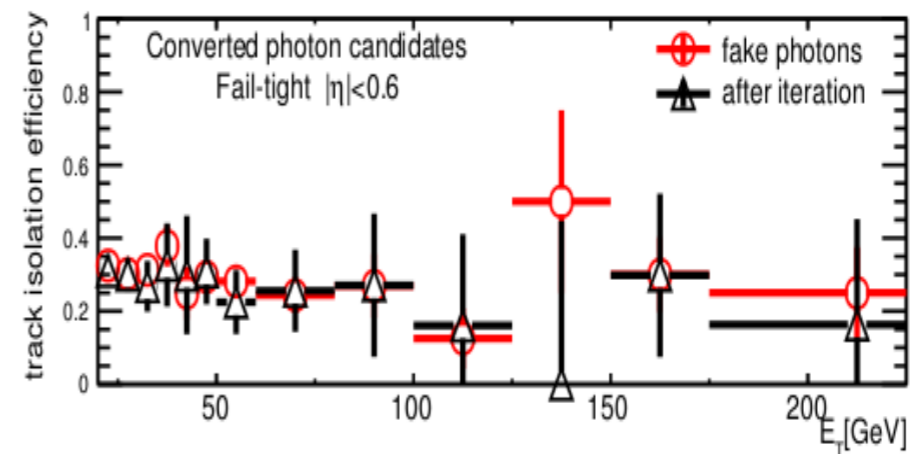
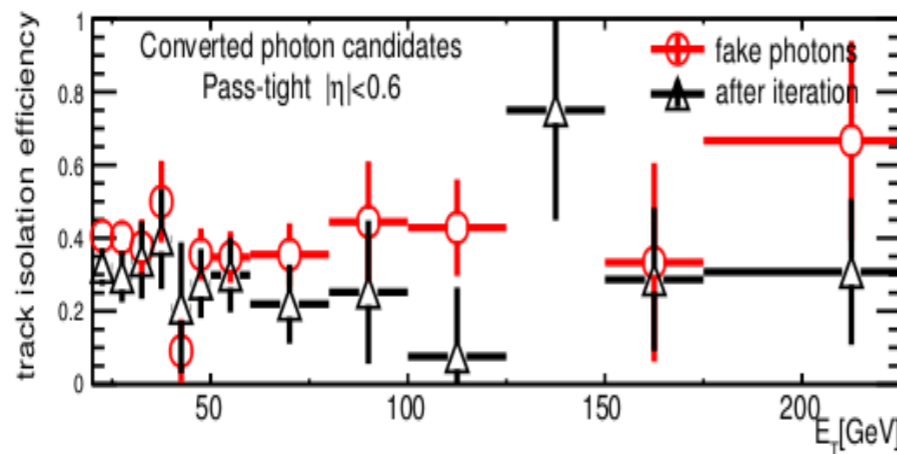
Bias on ε_p^b and ε_f^b in JF Monte Carlo

- In JF MC, compare the difference of ε_p^b and ε_f^b obtained with the truth match and the procedure used in data (bkg control sample and subtract signal leakage by using iteration)

unconverted photons



converted photons



- These difference is independent with E_T within statistical error. The average difference is taken as systematic uncertainty for each $|\eta|$ region passing or not tight criteria..